DANA			Material Analysis Report		MAR No.	041204	
Glacier Vandervell Bearings					Date	12/7/04	
Customer Name			Mack - TEI				
Identification of Samples							
Qty	Part N	umber	Description	Date Stamp(s)	Material	Mfg Loc.	
6			Rod Bearings				
Application			T-10 Test				
Reported History		ry					
Instructions			Prepare for comparison to previous analyses, Overlay and Ni layer thickness OD flash chemistry EDS map of overlay				
Requested by				Date Required	12/13/04		
Analysis Layer thicknesses are normal for overlay and nickel barrier. Flash layer cannot be directly measured. Lead/Tin content in the OD Flash is approximately 65/35 by SEM analysis, which is reasonable given the instrument's accuracy for this type of analysis. EDS mapping of composition shows Tin is still evenly distributed throughout the overlay and minimal Tin migration.							
Observations / Comments							
Reference previous MAR's # 040216 and 040311							
Met. La	ab	T Greave	es —	Date	12/09/04		
Engine	ering	D Lonows	ski	Completed			

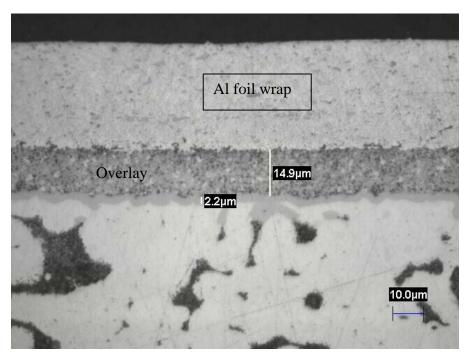


Figure 1 Thickness of Overlay and Nickel layers

Site: OD Flash

Sample: Sample 1 Processing option : All elements analysed (Normalised)

All results in weight%

Spectrum	Sn	Pb	Total
Spectrum 1	35.29	64.71	100.00
Spectrum 2	34.60	65.40	100.00
Spectrum 3	35.16	64.84	100.00
Mean	35.02	64.98	100.00
Std. deviation	0.37	0.37	
Max.	35.29	65.40	
Min.	34.60	64.71	

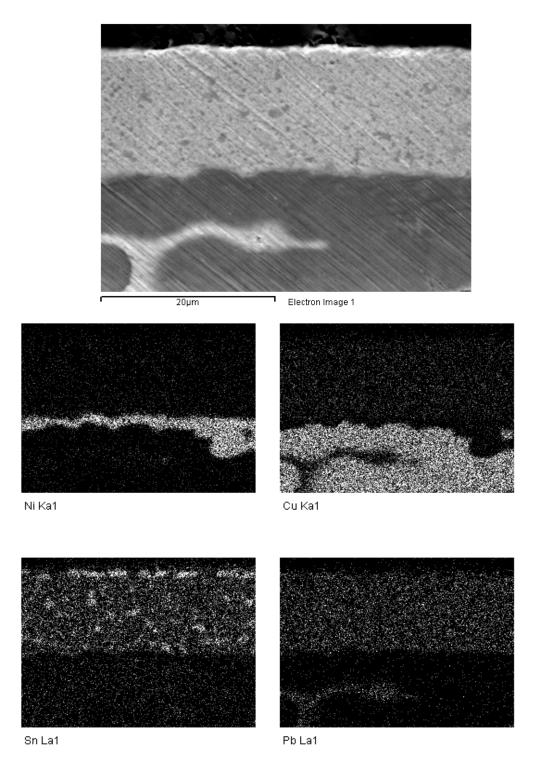


Figure 2 EDS mapping of overlay. Tin is still fairly well distributed throughout the overlay, with some concentration at the top from the flash layer.